

**Search Notes**

Application/Control No.

10/642,266

Examiner

Vuthe Siek

Applicant(s)/Patent under  
Reexamination

NAKANO ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	2,5,8- 11,19-21	3/30/2005	VS
430	5,311,313	3/30/2005	VS
438	57-60	3/30/2005	VS
438	514	3/30/2005	VS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST ALL DATABASES	3/30/2005	VS